

Record 1 of 1

Title: Evaluating Representation Learning of Code Changes for Predicting Patch Correctness in Program Repair
Author(s): Tian, HY (Tian, Haoye); Liu, K (Liu, Kui); Kabore, AK (Kabore, Abdoul Kader); Koyuncu, A (Koyuncu, Anil); Li, L (Li, Li); Klein, J (Klein, Jacques); Bissyande, TF (Bissyande, Tegawende F.)
Book Group Author(s): IEEE Comp Soc
Source: 2020 35TH IEEE/ACM INTERNATIONAL CONFERENCE ON AUTOMATED SOFTWARE ENGINEERING (ASE 2020) **Book Series:** IEEE ACM International Conference on Automated Software Engineering **Pages:** 981-992 **DOI:** 10.1145/3324884.3416532 **Published:** 2020
Accession Number: WOS:000651313500082
Conference Title: 35th IEEE/ACM International Conference on Automated Software Engineering (ASE)
Conference Date: SEP 21-25, 2020
Conference Location: ELECTR NETWORK
Conference Sponsors: IEEE, Assoc Comp Machinery, IEEE Comp Soc, Monash Univ, NASA Ames Rese Ctr, IEEE Tech Council Software Engn, ACM SIGAI, ACM Special Interest Grp Software Engn, Deakin Univ
Author Identifiers:

Author	Web of Science ResearcherID	ORCID Number
Klein, Jacques		0000-0003-4052-475X

ISSN: 1527-1366
ISBN: 978-1-4503-6768-4